PA300PS-MA

Fine-pitch probing with advanced probe cards

Unique microscope solution

- High-stability microscope support
- Largest movement area within EMI/RFI-shielded environment
- Your choice of microscope from FS70 with four objectives to iVista™ high-resolution digital microscope

Advanced EMI/RFI shielding -

- Lowest spectral noise (< -170 dbVrms/rtHz)
- Lowest system AC noise (< 4 mVpp)
- Best shielding effectiveness (> 30 dB)
- Completely light tight

Vibration-free, spring-balanced EMI shield covers

- Instantaneous access to measurement setup
- DUT remains ice and condensation-free when open

Instrument shelf for easy access to measurement equipment

Automated Thermal Management™ -

- Provides temperature stability of all active devices like RSU, PreAmp or LFN amplifier
- Automated control depending on chuck temperature
- Shorter time to reach thermal equilibrium before testing
- ullet ReAlignTM option to enable unattended tests over multiple temperatures

Flexible feedthrough options -

- Multiple locations for coaxial, triaxial and RF cables
- EMC compliant, light tight

MicroAlign™ -

- Performs ReAlign with off-axis pad-viewing camera
- Enables engineering tests with vertical probe cards
- The only solution for fine-pitch probing down to 30 μ m x 30 μ m pads

Ergonomic low-profile system design —

Probe card adapter with integrated ProtecPlate™ -

- Extra shielding over the DUT
- No mechanical changeover needed for probe card use

Automatic QuietMode™ -

- Eliminates noise by removing power from motorized stages
- Includes chuck stage, microscope stage and any motorized positioners
- Automatically engages when in contact

ProtecDrive™ technology

- Shields all drive systems
- Lowest impedance grounding
- Best low-level measurements

Powerful ProberBench™ operating environment

- Stable, Linux-based controller
- Integrated, reliable industrial PC for running ProberBench software

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• Easy integration with all test software from vendors such as Keithley and Agilent

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Advanced software automation tools

- Patented Auto CalSite Alignment
- AutoAlign feature
- Powerful pattern recognition software

Patented ContactView™ system

- Visual contact monitoring to eliminate damage to wafers and probes
- ProbeHorizon™ sets a safe working distance and moves wafers into view automatically after loading

Large EMI/RFI-shielded enclosure

- Flexible measurement setup with up to 10 positioners
- Use positioners and probe cards simultaneously in an EMI-shielded environment
- Integrate sensitive measurement equipment such as pre-amplifiers
- Shortest cable lengths

Seamless InteGration for Measurement Accuracy (SIGMA™)

- Ensures optimum measurement performance for all common and advanced measurement setups
- Easy to install and easy to use link between probes and the corresponding measurement equipment

Expert control panel

- Comfortable use without PC
- Full control of all probe stages with position feedback

Unique IntelliControl™ system control concept

- Entire system control from one panel
- Includes control of measurement equipment
- Analog joystick for precise, sub-micron positioning
- Point-and-shoot navigation
- Quick access to USB ports

Instant access to auxilliary chucks

- Located on forward position of loading mechanism
- Patented Auto CalSite Alignment detects the position of calibration substrates and automates the calibration procedure

Patented loading mechanism

- Keeps sensitive elements (chuck, stage) in place
- Reduces contamination to a minimum
- Reduces thermal conditioning times

Superior thermal performance from -60°C to 300°C

- Actively cooled platen reduces thermal drift
- New materials technology reduces conditioning times

Automated data generation

- Test routines run automatically with minimal operator intervention
- ReAlign technology automatically adjusts alignment after every temperature change to compensate for thermal drift

Integrated vibration isolation system

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

System height adjustment

